

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	18477	((29/827,593,829,831,832,840, 841,842,843,855) or (156/64) or (324/759) or (438/14,15,17,107, 108,110,111,112,113,125,126, 127)).CCLS.	US-PGPUB; USPAT	OR	OFF	2007/05/07 09:39
L2	711	I1 and @pd>"20061201"	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/07 09:40
L3	320	I2 and wafer	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/07 09:41
L4	48	I2 and wafer and grinding	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/07 09:43
L5	5	I2 and wafer map	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/07 09:43
S1	1927	EDS with wafer	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:18
S2	2	EDS with wafer with ink	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:18
S3	73	EDS with wafer with test	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:25
S4	0	EDS with wafer with lapping with ink	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/07 09:37
S5	1	EDS with lapping with ink	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:22
S6	80	EDS same lapping same ink	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:22
S7	0	EDS same lapping same ink same wafer	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:22
S8	5	test\$3 same lapping same ink same wafer	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:22
S9	9	EDS with wafer with lapping	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:49

## EAST Search History

S10	1	die sorting with wafer with (lapping or grinding)	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:53
S11	148	(test or testing or sorting) with wafer with (lapping or grinding)	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:54
S12	0	(test or testing or sorting) with wafer with (lapping or grinding) with ink	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/04/30 12:54